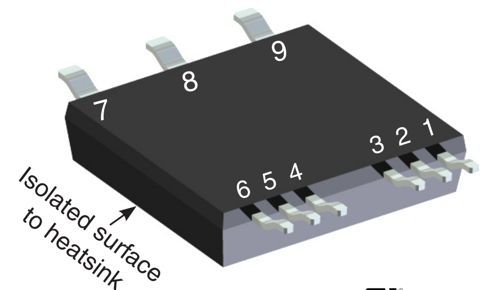
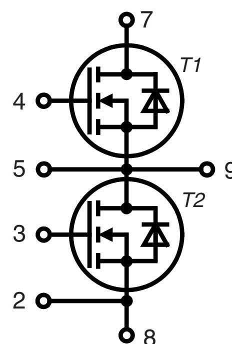
SiC Power MOSFET

I_{D25} = 25.5 A
V_{DSS} = 1200 V
$R_{DS(on)\,max}$ = 98 mΩ

Part number
MCB20P1200LB





Features / Advantages:
- High speed switching with low capacitances
- High blocking voltage with low $R_{DS(on)}$
- Easy to parallel and simple to drive
- Resistant to latch-up
- Real Kelvin source connection

Applications:
- Solar inverters
- High voltage DC/DC converters
- Motor drives
- Switch mode power supplies
- UPS
- Battery chargers
- Induction heating

Package: SMPD
- DCB isolated backside
- Isolation Voltage 2500 V
- Epoxy meets UL 94V-0
- RoHS compliant
- Advanced power cycling

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MOSFET				Ratings		
Symbol	Definitions	Conditions	min.	typ.	max.	
V_{DSS}	*drain source breakdown voltage*	V_{GS} = 0 V, I_D = 100 µA	1200			V
V_{GSM} V_{GS}	*max transient gate source voltage* *continous gate source voltage*	recommended operational value	-10 -5		+25 +20	V V
I_{D25} I_{D80} I_{D100}	*drain current*	V_{GS} = 20 V; T_C = 25°C T_C = 80°C T_C = 100°C			25.5 20.5 18	A A A
R_{DSon}	*static drain source on resistance*	I_D = 50 A; V_{GS} = 20 V; T_{VJ} = 25°C T_{VJ} = 175°C		80 155	98	mΩ mΩ
$V_{GS(th)}$	*gate threshold voltage*	I_D = 5 mA; V_{GS} = V_{DS}; T_{VJ} = 25°C T_{VJ} = 175°C	2.0	2.6 2.1	4.0	V V
I_{DSS}	*drain source leakage current*	V_{DS} = 1200 V; V_{GS} = 0 V; T_{VJ} = 25°C		2	100	µA
I_{GSS}	*gate source leakage current*	V_{DS} = 0 V; V_{GS} = 20 V; T_{VJ} = 25°C			250	nA
R_G	*internal gate resistance*	f = 1 MHz, V_{AC} = 25 mV, ESR of C_{ISS}		4.6		Ω
C_{iss} C_{oss} C_{rss}	*input capacitance* *output capacitance* *reverse transfer (Miller) capacitance*	V_{DS} = 1000 V; V_{GS} = 0 V; f = 1 MHz; T_{VJ} = 25°C		950 80 7.6		pF pF pF
Q_g Q_{gs} Q_{gd}	*total gate charge* *gate source charge* *gate drain (Miller) charge*	V_{DS} = 800 V; I_D = 40 A; V_{GS} = -5/20 V; T_{VJ} = 25°C		62 23 37		nC nC nC
$t_{d(on)}$ t_r $t_{d(off)}$ t_f E_{on} E_{off} $E_{rec(off)}$	*turn-on delay time* *current rise time* *turn-off delay time* *current fall time* *turn-on energy per pulse* *turn-off energy per pulse* *reverse recovery losses at turn-off*	Inductive switching V_{DS} = 800 V; I_D = 20 A; T_{VJ} = 25°C V_{GS} = -5 / 20 V; R_G = 22 Ω (external) Freewheeling diode is Mosfet's body diode		19 7 66 23 0.41 0.21 0.07		ns ns ns ns mJ mJ mJ
$t_{d(on)}$ t_r $t_{d(off)}$ t_f E_{on} E_{off} $E_{rec(off)}$	*turn-on delay time* *current rise time* *turn-off delay time* *current fall time* *turn-on energy per pulse* *turn-off energy per pulse* *reverse recovery losses at turn-off*	Inductive switching V_{DS} = 800 V; I_D = 20 A; T_{VJ} = 150°C V_{GS} = -5 / 20 V; R_G = 22 Ω (external) Freewheeling diode is Mosfet's body diode		18 7 75 21 0.49 0.20 0.10		ns ns ns ns mJ mJ mJ
R_{thJC} R_{thJH}	*thermal resistance junction to case* *thermal resistance junction to heatsink*	with heatsink compound; IXYS test setup		 1.5	1.0	K/W K/W

Source-Drain Diode				Ratings		
Symbol	Definitions	Conditions	min.	typ.	max.	
V_{SD}	*forward voltage drop*	I_F = 10 A; V_{GS} = -5 V; T_{VJ} = 25°C T_{VJ} = 150°C		3.3 3.1		V V
t_{rr} Q_{RM} I_{RM} dI_F/dt	*reverse recovery time* *reverse recovery charge (intrinsic diode)* *max. reverse recovery current* *current slew rate*	V_{GS} = -5 V; I_F = 20 A; V_R = 800 V; T_{VJ} = 25°C Mosfet gate drive: V_{GS} = -5 / 20 V; R_G = 22 Ω		15 0.20 23 3650		ns µC A A/µs
t_{rr} Q_{RM} I_{RM} dI_F/dt	*reverse recovery time* *reverse recovery charge (intrinsic diode)* *max. reverse recovery current* *current slew rate*	V_{GS} = -5 V; I_F = 20 A; V_R = 800 V; T_{VJ} = 150°C Mosfet gate drive: V_{GS} = -5 / 20 V; R_G = 22 Ω		19 0.42 35 4120		ns µC A A/µs

Note:
When using SiC Body Diode the maximum recommended V_{GS} = -5V

IXYS reserves the right to change limits, test conditions and dimensions. Data according ot IEC 60747 and per semiconductor unless otherwise specified 20220127c

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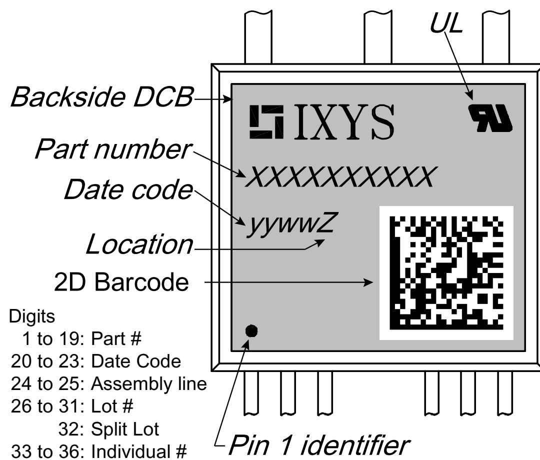
Package SMPD				Ratings		
Symbol	Definitions	Conditions	min.	typ.	max.	
I_{RMS}	*RMS current*	wide terminal standard terminal			100 60	A A
T_{stg} T_{op} T_{VJ}	*storage temperature* *opertation temperature* *virtual junction temperature*		-55 -55 -55		150 150 175	°C °C °C
Weight				8		g
F_C	*mounting force with clip*		40		130	N
$d_{Spp/App}$ $d_{Spb/Apb}$	*creepage distance on surface / striking distance through air*	terminal to terminal terminal to backside	1.6 4.0			mm mm
V_{ISOL}	*isolation voltage*	t = 1 second t = 1 minute 50/60 Hz; RMS; I_{ISOL} < 1 mA		3000 2500		V V



Part number

M = Mosfet
C = SiC MOSFET
B = Generation 2
20 = Current Rating [A]
P = Phase leg
1200 = Reverse Voltage [V]
LB = SMPD-B

Ordering	Part Name	Marking on Product	Delivering Mode	Base Qty	Ordering Code
Standard	MCB20P1200LB-TUB	MCB20P1200LB	Tube	20	MCB20P1200LB-TUB
Alternative	MCB20P1200LB-TRR	MCB20P1200LB	Tape&Reel	200	MCB20P1200LB-TRR

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Outlines SMPD-B

A (8 : 1)

(6x) 1 ± 0,05 [2)]

5,5 ± 0,1

0 + 0,15

2°

0,1

seating plane

25 ± 0,2 [1)]

0,5 ± 0,1

18 ± 0,1

9 ± 0,1

(3x) 2 ± 0,05 [2)]

4 ± 0,05

0,55 ± 0,1

7 8 9

23 ± 0,2

32,7 ± 0,5

2 ± 0,2

4,85 ± 0,2

3) 0,05

A

6 5 4 3 2 1

Pin number

2,75 ± 0,1

5,5 ± 0,1

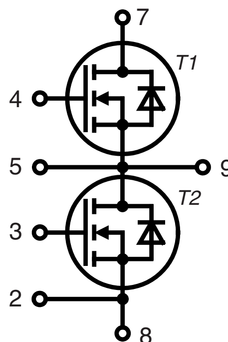
13,5 ± 0,1

16,25 ± 0,1

19 ± 0,1

Notes:
1) potrusion may add 0.2 mm max. on each side
2) additional max. 0.05 mm per side by punching misalignement
   or overlap of dam bar or bending compression
3) DCB area 10 to 50 µm convex;
   position of DCB area in relation to plastic rim: ±25 µm
   (measured 2 mm from Cu rim)
4) terminal plating: 2 - 6 µm Ni + 10 - 25 µm Sn (gal v.)
   cutting edges may be partially free of plating

Dimensions in mm
(1 mm = 0.0394“)



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Curves

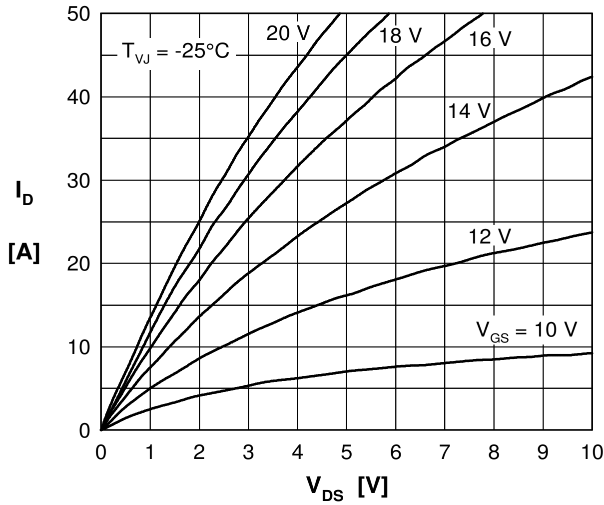

Fig. 1 Typical output characteristics (-25°C)

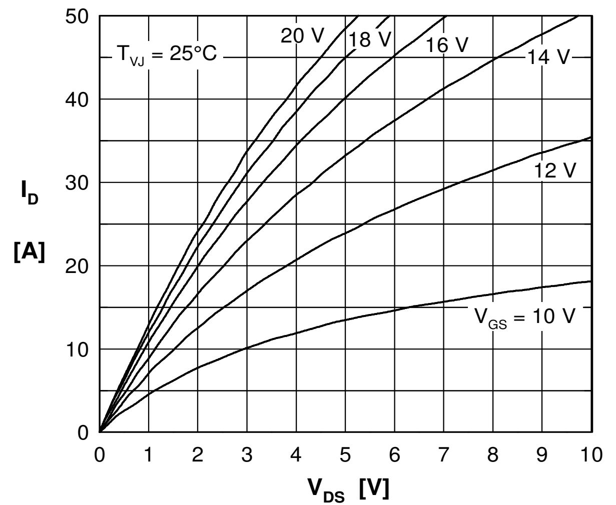

Fig. 2 Typical output characteristics (25°C)

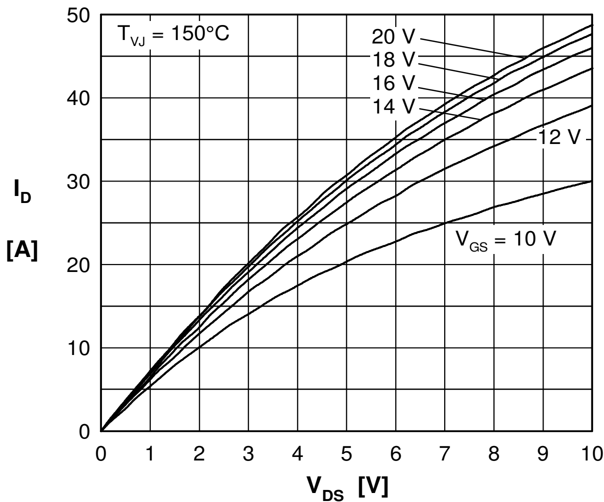

Fig. 3 Typical output characteristics (150°C)

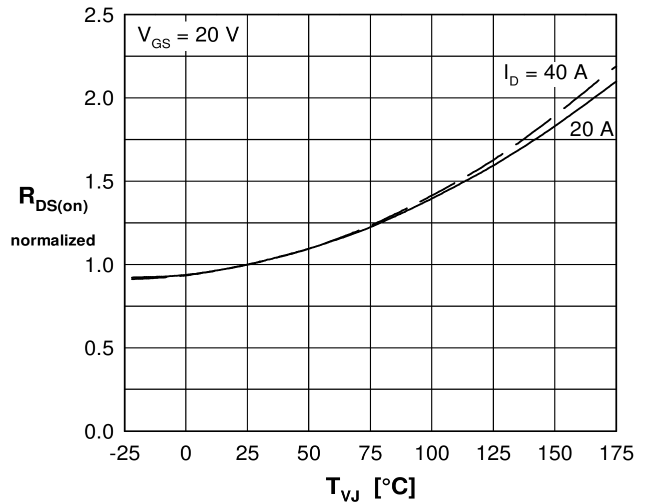

Fig. 4 $R_{DS(on)}$ normalized vs. junction temperature T_{VJ}

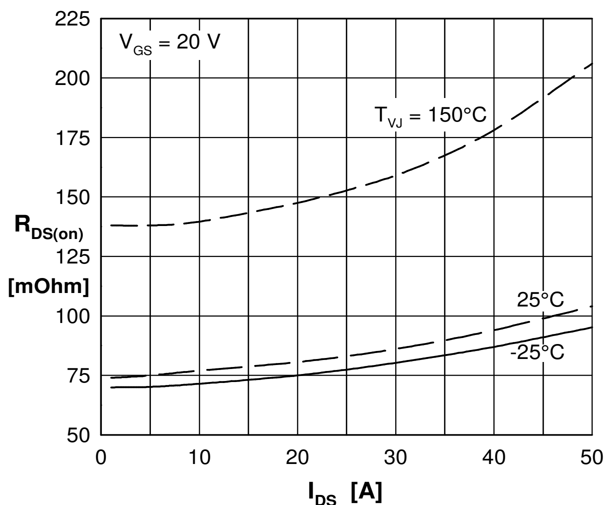

Fig. 5 $R_{DS(on)}$ versus drain current

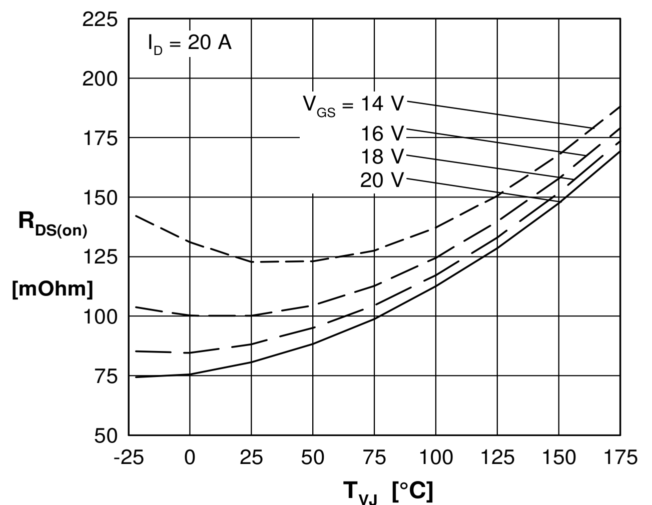

Fig. 6 $R_{DS(on)}$ versus junction temperature T_{VJ}

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Curves

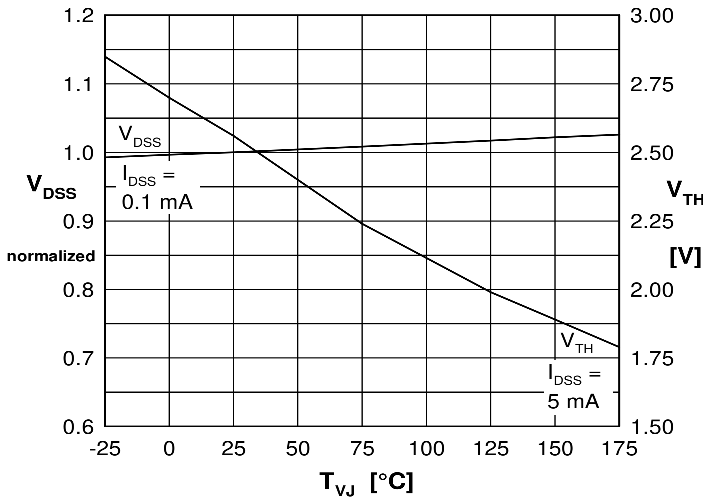

Fig. 7 Norm. breakdow V_{DSS} & treshhold voltage V_{TH} versus junction temperature T_{VJ}

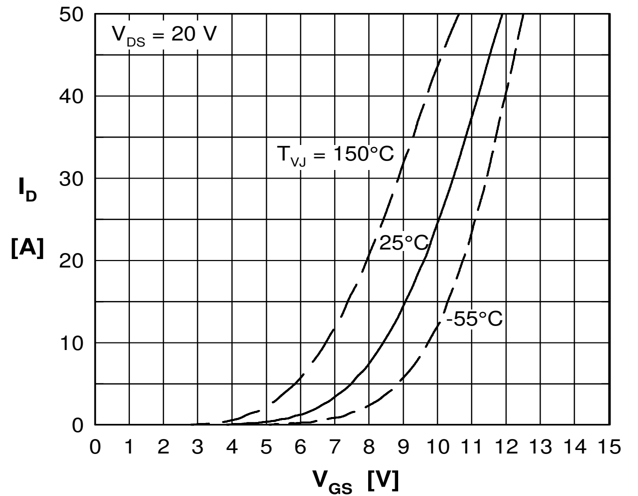

Fig. 8 Typical transfer characteristics

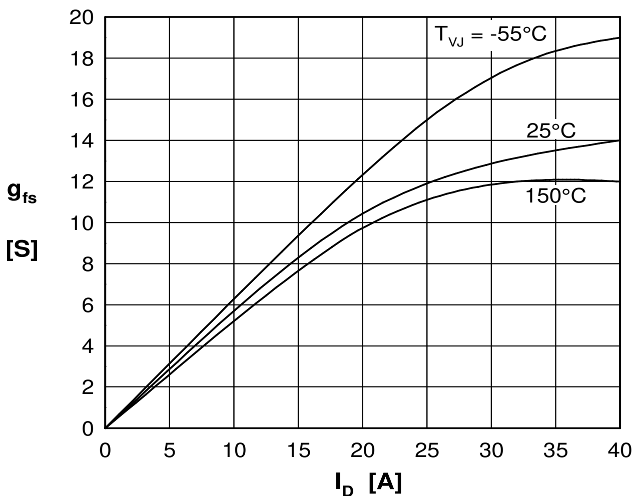

Fig. 9 Typical forward transconductance

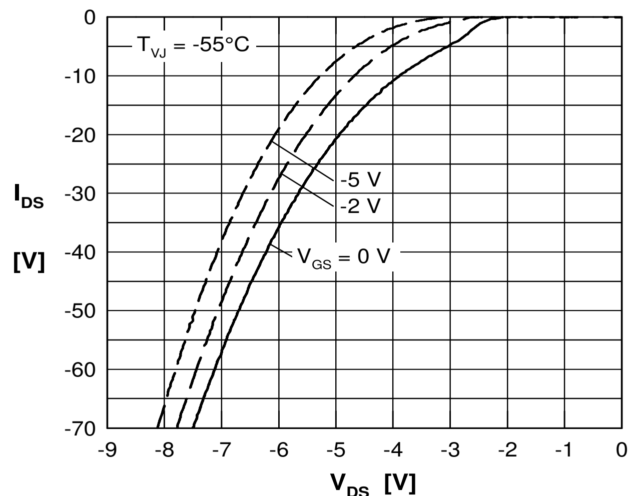

Fig. 10 Forward voltage drop of intrinsic diode versus V_{DS} measured at -55°C

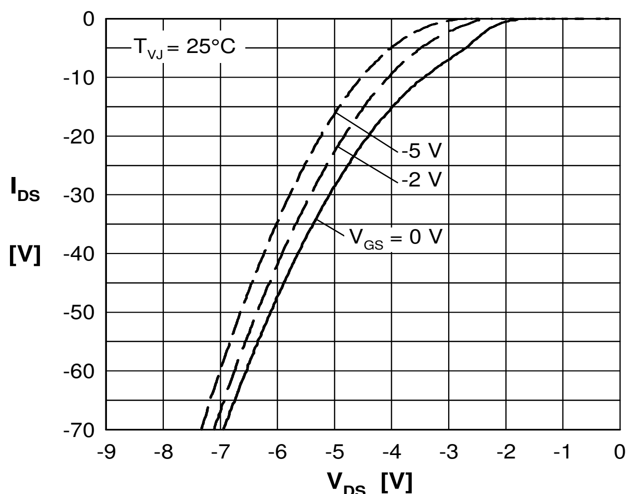

Fig. 11 Forward voltage drop of intrinsic diode versus V_{DS} measured at 25°C

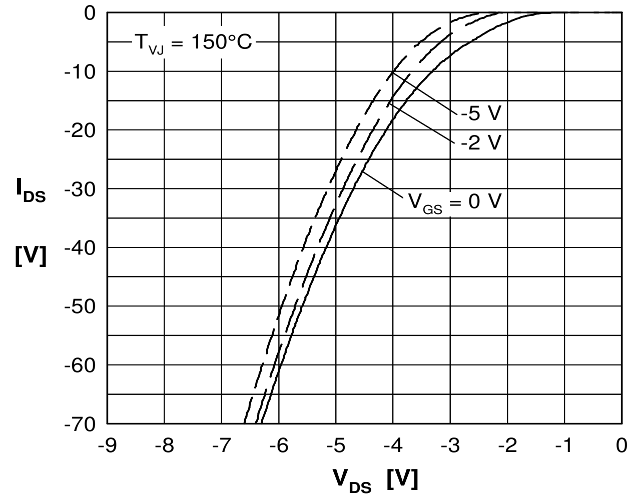

Fig. 12 Forward voltage drop of intrinsic diode versus V_{DS} measured at 150°C

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Curves

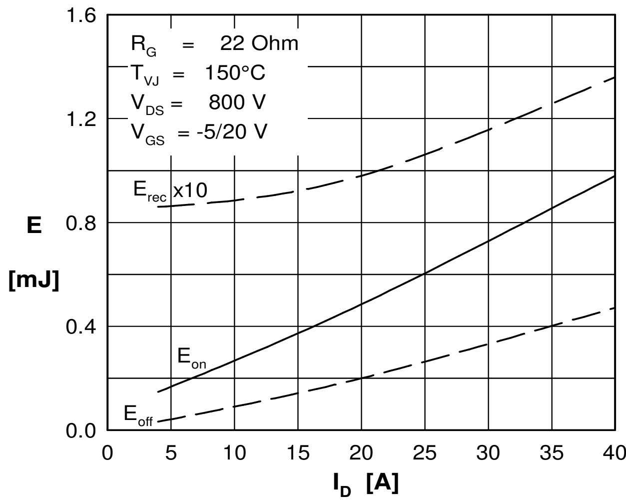

Fig. 13 Typical switching energy versus drain current

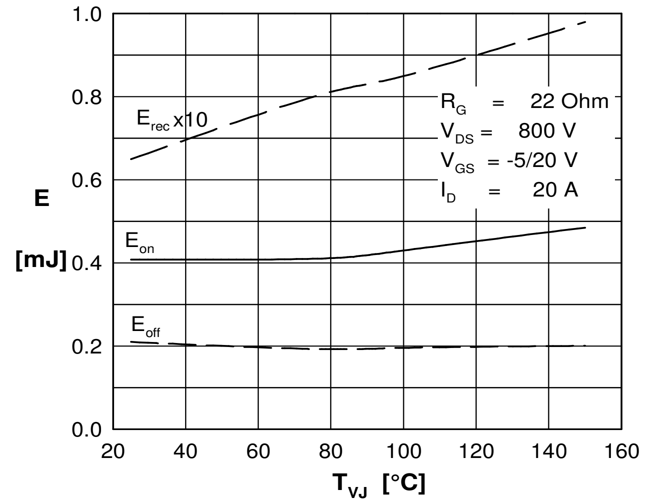

Fig. 14 Typical switching energy versus temperature

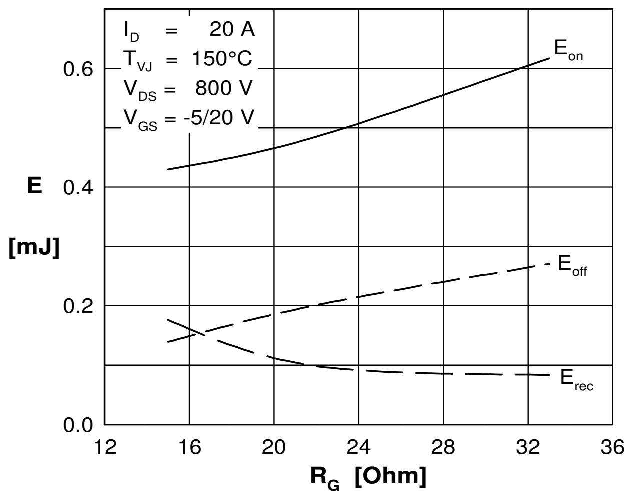

Fig. 15 Typical switching energy versus external gate resistor

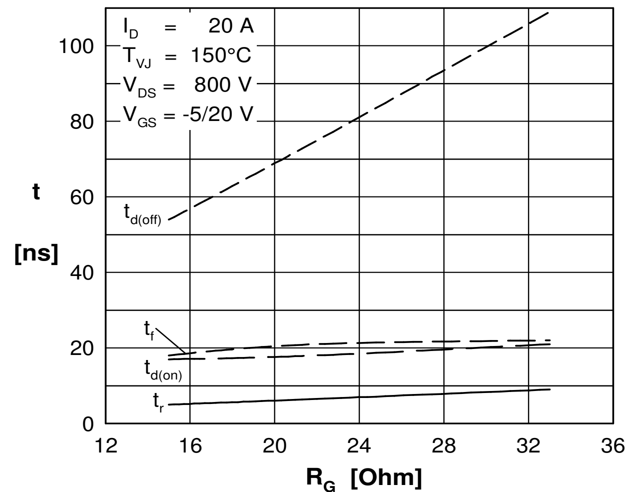

Fig. 16 Typical switching time versus external gate resistor

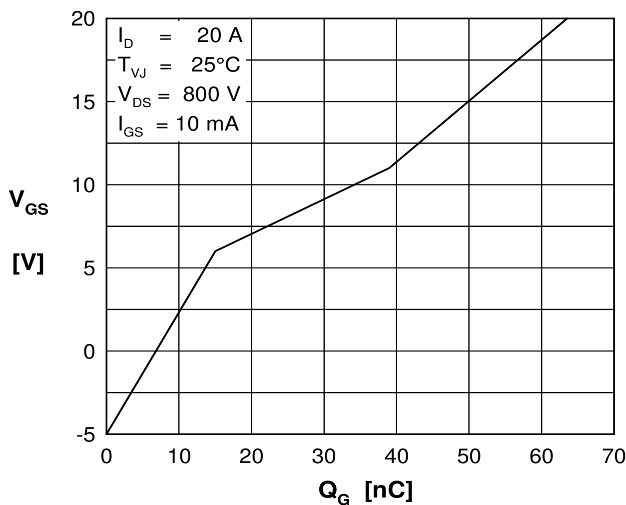

Fig. 17 Typical turn on gate charge, trendline

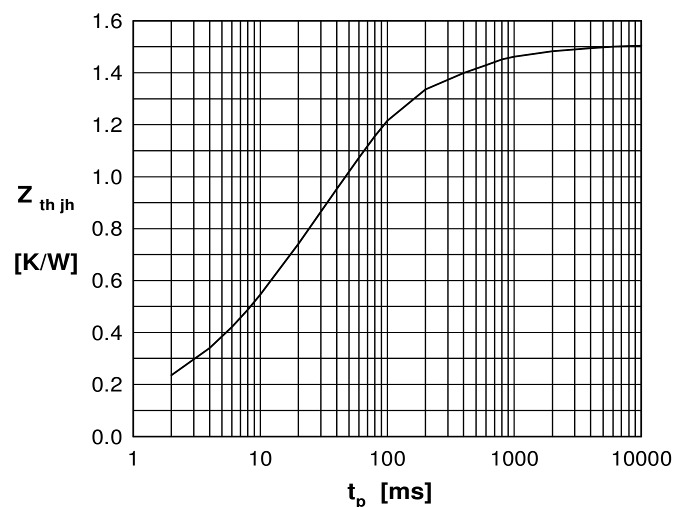

Fig. 18 Typical transient thermal impedance

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